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Contents

Editorial vii

Contents ix

Nanostructures

Influence of impurities on the density of states at the fermi level in the c(6 × 4)-C_{60}/Ag(1 0 0) two-dimensional superstructure
I. Vobornik, I. Avramova, L. Giovanelli, G. Panaccione, J. Fujii, S. Vobornik, C. Cepek, M. Sancrottti and G. Rossi 1

Interaction of molecular oxygen with single wall nanotubes: Role of surfactant contamination
R. Larciprete, A. Goldoni and S. Lizzit 5

Structural investigation of semiconductor nanostructures by X-ray techniques
J. Stangl, A. Hesse, T. Roch, V. Holý, G. Bauer, T. Schuelli and T.H. Metzger 11

Grazing incidence diffraction anomalous fine structure of self-assembled semiconductor nanostructures
S. Grenier, A. Letoublon, M.G. Proietti, H. Renevier, L. González, J.M. García, C. Priester and J. García 24

Atomic ordering in (InGa)(AsN) quantum wells: An In K-edge X-ray absorption investigation
G. Ciatto, F. Boscherini, F. D'Acapito, S. Mobilio, G. Baldassarri H.v.H, A. Polimeni, M. Capizzi, D. Gollub and A. Forchel 34

Influences of Si spacer layers on the structures of Ge/Si quantum dot bilayers
X. Jiang, T.H. Metzger, M. Sztucki, Z. Jiang, W. Jiang and D. Xian 40

AFM anodization studied by spectromicroscopy
M. Lazzarino, S. Heun, B. Ressel, K.C. Prince, P. Pingue and C. Ascoli 46

Semiconductors

Depth resolved investigations of boron implanted silicon
M. Sztucki, T.H. Metzger, S. Milita, F. Berberich, N. Schell, J.L. Rouvière and J. Patel 52

Lattice relaxation around impurity atoms in semiconductors – arsenic in silicon – a comparison between experiment and theory
V. Koteski, N. Ivanovic, H. Haas, E. Holub-Krappe and H.-E. Mahnke 60

XAFS characterization of buried $Si_xN_yO_z$ samples
F. Pinakidou, M. Katsikini and E.C. Paloura 66

GIXRD of nanoscale strain patterning in wafer bonding
J. Eymery, F. Leroy and F. Fournel 73

Spectro-microscopy of ultra-thin SiN films on Si (1 1 1)
Th. Schmidt, T. Clausen, S. Gangopadhyay, J. Falta, S. Heun, L. Gregoratti, A. Barinov, B. Kaulich and M. Kiskinova 79

$In_xGa_{(1-x)}As$ quantum dots grown on GaAs studied by EXAFS in total reflection mode (ReflEXAFS)
F. d'Acapito, S. Colonna, F. Arciprete, A. Balzarotti, I. Davoli, F. Patella and S. Mobilio 85

High-pressure X-ray diffraction study of InAs
G. Aquilanti, W.A. Crichton, T. Le Bihan and S. Pascarelli 90

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Anomalous diffraction in grazing incidence to study the strain induced by GaN quantum dots stacked in an AlN multilayer
V. Chamard, T.H. Metzger, M. Sztucki, M. Tolan, E. Bellet-Amalric, B. Daudin, C. Adelmann and H. Mariette 95
Local structure of iron implanted in indium phosphide
G. Ciatto, F. D'Acapito, B. Fraboni, F. Boscherini, N. El Habra, T. Cesca, A. Gasparotto, E.C. Moreira and F. Priolo 100
Small angle X-ray scattering study of oxygen precipitation in silicon
B. Pivac, P. Dubček, S. Bernstorff, A. Borghesi, A. Sassella and M. Porrini 105
GISAXS study of structural relaxation in amorphous silicon
P. Dubček, B. Pivac, S. Bernstorff, R. Tonini, F. Corni and G. Ottaviani 110
Microstructural characterization of $In_xGa_{1-x}N$ MBE samples
M. Katsikini, E.C. Paloura, F. Boscherini, F. D'Acapito, C.B. Lioutas and D. Doppalapudi 114
NEXAFS and AFM characterization of Si implanted GaN
M. Katsikini, F. Pinakidou, N. Vouroutzis, R. Mitdank, A. Markwitz and E.C. Paloura 120

Clusters and Micro-/Mesopouros Materials

Implanted dielectrics: Synchrotron radiation studies by absorption and diffraction techniques
C. Maurizio, F. Gonella, E. Cattaruzza, P. Mazzoldi and F. D'Acapito 126
GISAXS study of shape and size of CDS nanocrystals formed in monocrystalline silicon by ion implantation
P. Dubček, U.V. Desnica, I.D. Desnica-Franković, S. Bernstorff and A. Meldrum. 138
Size and ordering of sputtered Co nanoparticles in Co/Cu multilayers
F. Spizzo, F. Ronconi, F. Albertini, F. Casoli, L. Pareti, G. Turilli, F. Bolzoni, A. Mazuelas, C. Ferrero, G. Ghiringhelli, A. Tagliaferri and H. Metzger. 142
Characterisation of new hybrid organic–inorganic nickel silicates by polarised EXAFS
M. Richard-Plouet, M. Guillot, A. Traverse, D. Chateigner and S. Vilminot. 148
Characterization of isolated Ag cations in homoionic Ag-Y zeolites: A combined anomalous XRPD and EXAFS study
C. Lamberti, C. Prestipino, S. Bordiga, A.N. Fitch and G.L. Marra 155
Grazing incidence synchrotron X-ray diffraction study of crystal orientation in microporous films
S. Mintova, T.H. Metzger and T. Bein 160
Structure–activity relationships of heterogeneous catalysts from time-resolved X-ray absorption spectroscopy
T. Ressler, R.E. Jentoft, J. Wienold, F. Girgsdies, T. Neisius and O. Timpe 165
Formation and structure of Sn and Sb nanoclusters in thin SiO_2 films
S. Spiga, M. Fanciulli, N. Ferretti, F. Boscherini, F. D'Acapito, G. Ciatto and B. Schmidt 171
Deviation from the virtual crystal approximation in disordered Au–Cu alloy nanocrystals: EXAFS and GIXRD investigation
C. Maurizio, G. Mattei, P. Mazzoldi, S. Padovani, E. Cattaruzza, F. Gonella, F. D'Acapito and F. Zontone 178
Silver nanocluster formation in ion-exchanged glasses by annealing, ion beam and laser beam irradiation: An EXAFS study
G. Battaglin, E. Cattaruzza, F. Gonella, R. Polloni, F. D'Acapito, S. Colonna, G. Mattei, C. Maurizio, P. Mazzoldi, S. Padovani, C. Sada, A. Quaranta and A. Longo. 185
GISAXS studies of morphology and size distribution of CdS nanocrystals formed in SiO_2 by ion implantation
U.V. Desnica, P. Dubcek, I.D. Desnica-Frankovic, M. Buljan, K. Salamon, O. Milat, S. Bernstorff and C.W. White. 191
Description of a flexible cell for in situ X-ray and far-IR characterization of the surface of powdered materials
C. Lamberti, C. Prestipino, S. Bordiga, G. Berlier, G. Spoto, A. Zecchina, A. Laloni, F. La Manna, F. D'Anca, R. Felici, F. D'Acapito and P. Roy 196

Magnetism

Soft X-ray magnetic scattering as a probe of recording media
E.E. Fullerton, O. Hellwig, K. Takano and J.B. Kortright 202
Spin and orbital moments in Au/Co/Au(1 1 1)/W(1 1 0) across the spin-reorientation transition-temperature
K. Removic-Langer, J. Hunter Dunn, J. Langer, D. Arvanitis, H. Maletta and E. Holub-Krappe 210
Structure and magnetic properties in CoCu granular alloys
C. Meneghini, S. Mobilio, A. García-Prieto and M.L.F. Fdez-Gubieda 215
Resonant inelastic X-ray scattering from magnetic systems: Mn in $MnFe_2O_4$
P. Ferriani, G. Ghiringhelli, G. Ferrari, C.M. Bertoni, A. Tagliaferri, L. Braicovich and N.B. Brookes . 220

Oxides and Lattice Distortion

Charge ordering and local structure in manganese oxide perovskites studied by EXAFS
F. Bardelli, C. Meneghini, S. Mobilio, C. Castellano and V. Dediu 226
The thermal behaviour of cuprite: An XRD–EXAFS combined approach
M. Dapiaggi, W. Tiano, G. Artioli, A. Sanson and P. Fornasini 231
EXAFS and local thermal expansion: The case of silver oxide
S. a Beccara, G. Dalba, P. Fornasini, R. Grisenti, F. Rocca and A. Sanson 237
Photoemission spectroscopy study of the hole-doped Haldane chain $Y_{2-x}Sr_xBaNiO_5$
Y. Fagot-Revurat, D. Malterre, F.-X. Lannuzel, E. Janod, C. Payen, L. Gavioli and F. Bertran 242
Angle dependence of the O K edge absorption spectra of TiO_2 thin films with preferential texture
S. Räth, F. Gracia, F. Yubero, J.P. Holgado, A.I. Martin, D. Batchelor and A.R. González-Elipe 248

Engineering Materials

Precipitate scanning in Bi-base γ/γ'-superalloys
S.V. Roth, M. Burghammer, R. Gilles, D. Mukherji, J. Rösler and P. Strunz 255
Dislocation transmission through a $\Sigma = 3$ grain boundary in Fe 6 at.% Si: In situ experiments in compression specimen
A. Jacques, A. George, M. Polcarova and J. Bradler 261
X-ray grazing incidence study of inhomogeneous strain relaxation in Si/SiGe wires
A. Hesse, Y. Zhuang, V. Holý, J. Stangl, S. Zerlauth, F. Schäffler, G. Bauer, N. Darowski and U. Pietsch 267
X-ray micro-tomography an attractive characterisation technique in materials science
L. Salvo, P. Cloetens, E. Maire, S. Zabler, J.J. Blandin, J.Y. Buffière, W. Ludwig, E. Boller, D. Bellet and C. Josserond 273
In situ microtomography investigation of metal powder compacts during sintering
O. Lame, D. Bellet, M.D. Michiel and D. Bouvard 287
X-ray tomographic imaging of Al/SiC_p functionally graded composites fabricated by centrifugal casting
A. Velhinho, P.D. Sequeira, R. Martins, G. Vignoles, F. Braz Fernandes, J.D. Botas and L.A. Rocha . 295
Damage assessment in metallic structural materials using high resolution synchrotron X-ray tomography
L. Babout, W. Ludwig, E. Maire and J.Y. Buffière 303
Direct 3D microscale imaging of carbon–carbon composites with computed holotomography
O. Coindreau, G. Vignoles and P. Cloetens 308
Internal stress measurements by high-energy synchrotron X-ray diffraction at increased specimen-detector distance
J. Böhm, A. Wanner, R. Kampmann, H. Franz, K.-D. Liss, A. Schreyer and H. Clemens 315
X-ray "magnifying" imaging investigation of giant Burgers vector micropipe-dislocations in 4H-SiC
J. Härtwig, J. Baruchel, H. Kuhn, X.-R. Huang, M. Dudley and E. Pernot 323
Characterisation of grains in tungsten–carbon films
P. Dubček, N. Radić and O. Milat 329

Grain boundary liquid metal wetting: A synchrotron micro-radiographic investigation
E. Pereiro-López, W. Ludwig, D. Bellet and J. Baruchel 333
Mechanical testing device for in situ experiments on reversibility of dislocation motion in silicon
J.P. Feiereisen, O. Ferry, A. Jacques and A. George 339
The γ/γ' mismatch in Ni based superalloys: In situ measurements during a creep test
F. Diologent, P. Caron, T. d'Almeida, A. Jacques and P. Bastie 346
Study by microtomography of 3D porosity networks in irradiated beryllium
E. Rabaglino, J. Baruchel, E. Boller, A. Elmoutaouakkil, C. Ferrero, C. Ronchi and T. Wiss 352
Synchrotron topography of high temperature–pressure treated silicon implanted with helium
A. Misiuk, W. Wierzchowski, K. Wieteska, L. Bryja and W. Graeff 358

Surface and Interfaces

The structure of organic langmuir films on liquid metal surfaces
H. Kraack, M. Deutsch, B.M. Ocko and P.S. Pershan 363
Ni atomic environment in epitaxial NiO layers on Ag(0 0 1)
P. Luches, E. Groppo, C. Prestipino, C. Lamberti, C. Giovanardi and F. Boscherini 371
Time-resolved photoelectron spectroscopy of oxidation on the Ti (0 0 0 1) surface
Y. Takakuwa, S. Ishidzuka, A. Yoshigoe, Y. Teraoka, Y. Mizuno, H. Tonda and T. Homma 376

Biomaterials/Techniques

Non-destructive microstructural analysis with depth resolution
E. Zolotoyabko and J.P. Quintana 382
Scanning X-ray microdiffraction of complex materials: Diffraction geometry considerations
O. Paris and M. Müller 390
Tomography studies of human foreskin fibroblasts on polymer yarns
P. Thurner, B. Müller, F. Beckmann, T. Weitkamp, C. Rau, R. Müller, J.A. Hubbell and U. Sennhauser 397
Structure of bioapatite in human foetal bones: An X-ray diffraction study
M.C. Dalconi, C. Meneghini, S. Nuzzo, R. Wenk and S. Mobilio 406
Order in poly(di-*n*-alkyl itaconate)s revealed by X-ray scattering experiments
P.F. Holmes, V. Arrighi, I.J. McEwen, H. Qian and N.J. Terrill 411
Poly(tetrafluoroethylene) under pressure: X-diffraction studies
M. Lorenzen, M. Hanfland and A. Mermet 416
Probing the initial stages of solid-state reactions by total reflection EXAFS (reflEXAFS)
F. d'Acapito, P. Ghigna, I. Alessandri, A. Cardelli and I. Davoli 421
XAS study of chromium in Li_2MSiO_4 (M = Mg, Zn)
C. Jousseaume, F. Ribot, A. Kahn-Harari, D. Vivien and F. Villain 425
Pulse plating of Pt on n-GaAs (100) wafer surfaces: Synchrotron induced photoelectron spectroscopy and XPS of wet fabrication processes
D. Ensling, R. Hunger, D. Kraft, Th. Mayer, W. Jaegermann, M. Rodriguez-Girones, V. Ichizli and H.L. Hartnagel 432
High pressure and high temperature X-ray diffraction study of InAs
S. Pascarelli, G. Aquilanti, P. Munsch and J.P. Itié 439
Microimaging and tomography with chemical speciation
C. Rau, A. Somogyi and A. Simionovici 444

Author index 451